



Information Disclosure Statement by Applicant (use as many sheets as necessary)				Complete if Known	
Sheet	1	of	12	Application Number	10/644,844
				Filing Date	August 19, 2003
				First Named Inventor	Henley, Francois J.
				Art Unit	Not Yet Assigned 2P23
				Examiner Name	Not Yet Assigned H. Lee
				Attorney Docket Number	018419-000183US

U.S. PATENT DOCUMENTS*					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number Number Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Column, Lines, Where Relevant Passages or Relevant Figures Appear
<i>Jee</i>	1	2,614,055	10/1952	Sorenson	
	2	3,117,022	01/1964	Bronson et al.	
	3	3,225,820	12/1995	Riordan	
	4	3,390,033	06/1968	Brown	
	5	3,551,213	12/1970	Boyle	
	6	3,770,499	10/1973	Crowe et al.	
	7	3,786,359	01/1974	King	
	8	3,806,380	04/1974	Kituda et al.	
	9	3,832,219	08/1974	Nelson et al.	
	10	3,900,636	08/1975	Curry et al.	
	11	3,901,423	08/1975	Hillberry et al.	
	12	3,915,757	10/1975	Engel	
	13	3,946,334	03/1976	Yonezu et al.	
	14	3,957,107	05/1976	Altaz et al.	
	15	3,993,909	11/1976	Drews et al.	
	16	4,006,340	02/1977	Gorines	
	17	4,039,416	08/1977	White	
	18	4,053,335	10/1977	Hu	
	19	4,074,139	02/1978	Pankove	
	20	4,107,350	08/1978	Berg et al.	
	21	4,108,751	08/1978	King	
	22	4,116,751	09/1978	Zaromb	
	23	4,121,334	10/1978	Wallis	
	24	4,170,662	10/1979	Weiss et al.	
	25	4,216,906	08/1980	Olsen et al.	
	26	4,237,601	12/1980	Woolhouse et al.	
	27	4,244,348	01/1981	Wilkes	
	28	4,252,837	02/1981	Auton	
<i>Jee</i>	29	4,255,208	03/1981	Deutscher et al.	

Examiner Signature	<i>Asier Mij Lee</i>	Date Considered	<i>6/22/05</i>
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60070501 v1

*paper NO. : 012304*



Substitute for form 1449A/PTO				<i>Complete if Known</i>	
				Application Number	10/644,644
				Filing Date	August 19, 2003
				First Named Inventor	Henley, Francois J.
				Art Unit	Not Yet Assigned <i>2P2</i>
				Examiner Name	Not Yet Assigned <i>H. Lee</i>
Sheet	2	of	12	Attorney Docket Number	018419-000183US

U.S. PATENT DOCUMENTS*					
Examiner Initials*	Cita No. <sup>1</sup>	Document Number Number Kind Code <sup>3</sup> (If Known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columna, Linea, Where Relevant Passages or Relevant Figures Appear
<i>Lee</i>	30	4,374,004	06/1981	Kanai	
	31	4,342,631	08/1982	White et al.	
	32	4,346,123	08/1982	Kaufmann	
	33	4,361,600	11/1982	Brown	
	34	4,368,083	01/1983	Bruel et al.	
	35	4,375,125	03/1983	Byatt	
	36	4,412,868	11/1983	Brown et al.	
	37	4,452,644	06/1984	Bruel et al.	
	38	4,468,309	08/1984	White	
	39	4,471,003	09/1984	Cann	
	40	4,486,247	12/1984	Ecer et al.	
	41	4,490,190	12/1984	Speri	
	42	4,500,563	02/1985	Ellenberger et al.	
	43	4,508,056	04/1985	Bruel et al.	
	44	4,536,657	08/1985	Bruel	
	45	4,539,050	09/1985	Kramler et al.	
	46	4,566,403	01/1986	Fournier	
	47	4,567,505	01/1986	Pease et al.	
	48	4,568,563	02/1986	Jackson et al.	
	49	4,585,945	04/1986	Bruel et al.	
	50	4,645,546	02/1987	Matsushita	
	51	4,684,535	08/1987	Heinecke et al.	
	52	4,704,302	11/1987	Bruel et al.	
	53	4,706,377	11/1987	Shuskus	
	54	4,717,683	01/1988	Parrillo et al.	
	55	4,727,047	02/1988	Bozler et al.	
	56	4,764,394	08/1988	Conrad	
<i>Lee</i>	57	4,766,086	08/1988	Ohshima et al.	
<i>Lee</i>	58	4,837,172	06/1989	Mizuno et al.	

Examiner Signature	<i>Paul Mij Lee</i>	Date Considered	<i>6/22/05</i>
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Information Disclosure Statement by Applicant <i>(use as many sheets as necessary)</i>				Complete if Known	
Sheet	3	of	12	Application Number	10/644,644
				Filing Date	August 19, 2003
				First Named Inventor	Henley, Francois J.
				Art Unit	Not Yet Assigned 2521
				Examiner Name	Not Yet Assigned H. Lee
				Attorney Docket Number	018419-000183US

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	59	4,846,928	07/1989	Dolins et al.	
	60	4,847,792	07/1989	Barna et al.	
	61	4,853,250	08/1989	Boulos et al.	
	62	4,883,561	11/1989	Gmitter et al.	
	63	4,887,005	12/1989	Rough et al.	
	64	4,891,329	01/1990	Reisman et al.	
	65	4,894,709	01/1990	Phillips et al.	
	66	4,931,405	06/1990	Kamijo et al.	
	67	4,948,458	08/1990	Ogle	
	68	4,952,273	08/1990	Popov	
	69	4,956,693	09/1990	Sawahata et al.	
	70	4,960,073	10/1990	Suzuki et al.	
	71	4,982,090	01/1991	Wittmaack	
	72	4,983,251	01/1991	Haisma et al.	
	73	4,996,077	02/1991	Moslehi et al.	
	74	5,015,353	03/1991	Hubler et al.	
	75	5,034,343	07/1991	Rouse et al.	
	76	5,070,040	12/1991	Pankove	
	77	5,082,793	01/1992	Li	
	78	5,102,821	04/1992	Moslchi	
	79	5,110,748	05/1992	Sarma	
	80	5,133,826	07/1992	Dandi	
	81	5,162,241	11/1992	Mori et al.	
	82	5,196,355	03/1993	Wittkower	
	83	5,198,371	03/1993	Li	
	84	5,202,095	04/1993	Houchin et al.	
	85	5,203,960	04/1993	Dandi	
	86	5,206,749	04/1993	Zavacky et al.	
	87	5,213,451	05/1993	Frank	

Examiner Signature	<i>Kris May Lee</i>	Date Considered	6/22/05
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Substitute for form 1449A PTO				Complete If Known	
				Application Number	10/644,644
				Filing Date	August 19, 2003
				First Named Inventor	Henley, Francois J.
				Art Unit	Not Yet Assigned 2825
				Examiner Name	Not Yet Assigned H. Lee
Sheet	4	of	12	Attorney Docket Number	018419-000183US

U.S. PATENT DOCUMENTS*					
Examiner Initiating	Cite No. <sup>1</sup>	Document Number Number Kind Code <sup>2</sup> (If known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Column, Lines, Where Relevant Passages or Relevant Figures Appear
	88	5,234,529	08/1993	Johnson	
	89	5,234,535	08/1993	Beyer et al.	
	90	5,242,861	09/1993	Inaba	
	91	5,250,328	10/1993	Otto	
	92	5,252,178	10/1993	Moslehi	
	93	5,256,562	10/1993	Vu et al.	
	94	5,258,320	11/1993	Zavacky et al.	
	95	5,258,325	11/1993	Spitzer et al.	
	96	5,269,880	12/1993	Jolly et al.	
	97	5,273,610	12/1993	Thomas, III et al.	
	98	5,277,748	01/1994	Sakaguchi et al.	
	99	5,303,574	04/1994	Matossian et al.	
	100	5,304,509	04/1994	Sopori	
	101	5,308,776	05/1994	Goto	
	102	5,317,236	05/1994	Zavacky et al.	
	103	5,342,472	08/1994	Imahashi et al.	
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	105	5,354,381	10/1994	Sheng	
	106	5,362,671	11/1994	Zavacky et al.	
	107	5,363,603	11/1994	Miller et al.	
	108	5,368,710	11/1994	Chen et al.	
	109	5,370,765	12/1994	Dandl	
	110	5,374,564	12/1994	Bruci	
	111	5,376,560	12/1994	Aronowitz et al.	
	112	5,377,031	12/1994	Vu et al.	
	113	5,404,079	04/1995	Ohkuni et al.	
	114	5,405,480	04/1995	Benzing et al.	
	115	5,411,592	05/1995	Ovshinsky et al.	
	116	5,413,679	05/1995	Godfrey	

Examiner Signature	<i>Han My Lee</i>	Date Considered	6/2/05
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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>				Application Number	10/644,644
(use as many sheets as necessary)				Filing Date	August 19, 2003
Sheet	5	of	12	First Named Inventor	Henley, Francois J.
				Art Unit	Not Yet Assigned 2823
				Examiner Name	Not Yet Assigned H. Lee
				Attorney Docket Number	018419-000183US

U.S. PATENT DOCUMENTS*					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number Number Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
Lee	117	5,435,880	07/1995	Minato et al.	
	118	5,438,241	08/1995	Zavacky et al.	
	119	5,443,661	08/1995	Oguro et al.	
	120	5,444,557	08/1995	Spitzer et al.	
	121	5,459,016	10/1995	Debe et al.	
	122	5,475,514	12/1995	Salerno et al.	
	123	5,476,691	12/1995	Konvopoulos et al.	
	124	5,480,842	01/1996	Clifton et al.	
	125	5,487,785	01/1996	Horiike et al.	
	126	5,494,835	02/1996	Bruel	
	127	5,504,328	04/1996	Bonser	
	128	5,528,397	06/1996	Zavacky et al.	
	129	5,539,245	06/1996	Imura et al.	
	130	5,558,718	09/1996	Leung	
	131	5,559,043	09/1996	Bruel	
	132	5,569,620	10/1996	Linn et al.	
	133	5,581,385	12/1996	Spitzer et al.	
	134	5,585,304	12/1996	Hayashi et al.	
	135	5,611,835	03/1997	Wijarnarakul	
	136	5,643,834	07/1997	Harada et al.	
	137	5,653,811	08/1997	Chan	
	138	5,705,421	01/1998	Matsuzita et al.	
	139	5,710,057	01/1998	Kenney	
	140	5,714,395	02/1998	Bruel	
	141	5,744,852	04/1998	Linn et al.	
	142	5,753,560	05/1998	Hong et al.	
	143	5,755,914	05/1998	Yonchaya	
Lee	144	5,763,319	06/1998	Ling et al.	
Lee	145	5,783,022	07/1998	Cha et al.	

Examiner Signature	<i>Kevin May Lee</i>	Date Considered	6/22/05
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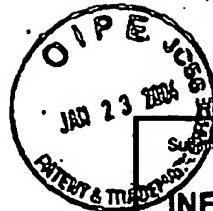


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				Application Number	10/644,644
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				First Named Inventor	Henley, Francois J.
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				Examiner Name	Not Yet Assigned H. Lee
Sheet	6	of	12	Attorney Docket Number	018419-000183US

U.S. PATENT DOCUMENTS*					
Examiner Initials	Cts No. <sup>1</sup>	Document Number Number &ndash; Code <sup>2</sup> (If known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
Lee	146	5,804,086	09/1998	Bruck	
	147	5,821,158	10/1998	Shiziguchi	
	148	5,824,595	10/1998	Igci et al.	
	149	5,827,751	10/1998	Nuyen	
	150	5,840,590	11/1998	Myers, Jr. et al.	
	151	5,854,123	12/1998	Sato et al.	
	152	5,869,387	02/1999	Sato et al.	
	153	5,877,070	03/1999	Goesele et al.	
	154	5,882,987	03/1999	Srikrishnan	
	155	5,909,627	06/1999	Egloff	
	156	5,920,764	07/1999	Hanson et al.	
	157	5,953,622	09/1999	Lee et al.	
	158	5,966,620	10/1999	Sakaguchi et al.	
	159	5,985,742	11/1999	Healey et al.	
	160	5,993,677	11/1999	Biasse et al.	
	161	5,994,207	11/1999	Henley et al.	
	162	6,010,579	01/2000	Healey et al.	
	163	6,013,563	01/2000	Henley et al.	
	164	6,020,252	02/2000	Aspar et al.	
	165	6,033,974	03/2000	Healey et al.	
	166	6,048,411	04/2000	Henley et al.	
	167	6,077,383	06/2000	Leporte	
	168	6,083,324	07/2000	Henley	
	169	6,120,597	09/2000	Levy et al.	
	170	6,150,239	11/2000	Goesele et al.	
	171	6,159,824	12/2000	Henley et al.	
	172	6,171,965	01/2001	Kang et al.	
Lee	173	6,184,111	02/2001	Healey et al.	

Examiner Signature	<i>Levon May Lee</i>	Date Considered	6/2/05
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<i>Lee</i>	174	6,190,998	02/2001	Brusil et al.	
<i>Lee</i>	175	6,191,007	02/2001	Matsui et al.	
<i>Lee</i>	176	6,214,701	04/2001	Matsushita et al.	
<i>Lee</i>	177	6,225,192	05/2001	Aspar et al.	

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Examiner Initials	Cite No.*	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T*
		Country Code <sup>4</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (If known)				
<i>Lee</i>	178	DE	0834363		03/1952		/	1
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	180	EP	0181249		06/1989		/	
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	182	EP	0533551		03/1993		/	
	183	EP	0379828		09/1993		/	
	184	EP	0459177		12/1993		/	
	185	EP	0703609		03/1996		/	
	186	EP	0763849		03/1997		/	
	187	EP	807 970	A1	11/1997		/	
	188	EP	0867921		03/1998		/	
	189	EP	0867 917	A2	09/1998		/	
	190	EP	961 312	A2	12/1999		/	
	191	EP	084 287	A1	07/1983		/	
	192	EP	099 778	A1	02/1984		/	
	193	EP	155 875	A1	02/1984		/	
	194	EP	112 230	A1	04/1987		/	
	195	EP	164 281	A1	12/1985		/	
	196	EP	181 249	A1	06/1989		/	
	197	EP	0355913		12/1993		/	
	198	EP	0665588		12/1995		/	
	199	EP	0660140		06/1995		/	
	200	EP	0665587		08/1995		/	
	201	FR	1558881		01/1969		/	

Examiner Signature	<i>Karen May Lee</i>	Date Considered	<i>6/22/05</i>
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# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet	8	of	12	Attorney Docket Number	018419-000183US
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FOREIGN PATENT DOCUMENTS							
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		Country Code <sup>3</sup>	Number <sup>4</sup>				
Jee	202	FR	2261802	02/1974			
	203	FR	2235474	04/1974			
	204	FR	2298880	01/1975			
	205	FR	2266304	04/1975			
	206	FR	2519437	01/1982			
	207	FR	2529383	06/1982			
	208	FR	2537768	08/1982			
	209	FR	2537777	12/1982			
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	211	FR	2560426	02/1984			
	212	FR	2563377	04/1984			
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	214	FR	2681472	09/1991			
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	216	FR	2715501	01/1994			
	217	FR	2715503	01/1994			
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Examiner Signature	Karen May Lee	Date Considered	6/22/05
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Substitute for form 1448A/PTO				Complete if Known	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>				Application Number	10/644,644
				Filing Date	August 19, 2003
				First Named Inventor	Henley, Francois J.
				Art Unit	Not Yet Assigned 2P21
				Examiner Name	Not Yet Assigned H. Lee
Sheet	9	of	12	Attorney Docket Number	018419-000183US

FOREIGN PATENT DOCUMENTS								
Examiner Initials	Cite No. <sup>1</sup>	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>4</sup>
		Country Code <sup>2</sup>	Number <sup>3</sup>	Kind Code <sup>4</sup> (If known)				
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Lee	254	WO	WO 99/35674		07/1999			

Examiner Signature	<i>Karen May Lee</i>	Date Considered	6/22/05
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Information Disclosure Statement by Applicant <i>(use as many sheets as necessary)</i>				Compliant if Known	
Sheet 10		of 12		Application Number	10/644,644
				Filing Date	August 19, 2003
				First Named Inventor	Henley, Francois J.
				Art Unit	Not Yet Assigned 2823
				Examiner Name	Not Yet Assigned H. Lee
				Attorney Docket Number	018419-000183US

NON PATENT LITERATURE DOCUMENTS					
Examiner Initials *	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			
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Examiner Signature	<i>Karen May Lee</i>	Date Considered	<i>6/2/05</i>
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Information Disclosure Statement by Applicant <i>(use as many sheets as necessary)</i>			
Sheet	11	of	12
<b>C mplete if Known</b> Application Number 10/644,644 Filing Date August 19, 2003 First Named Inventor Henley, Francois J. Art Unit Not Yet Assigned 2823 Examiner Name Not Yet Assigned H. IEE Attorney Docket Number 018419-000183US			

NON PATENT LITERATURE DOCUMENTS				
Examiner Initials *	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		
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Examiner Signature	<i>Karen May Lee</i>	Date Considered	<i>6/2/05</i>
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Information Disclosure Statement by Applicant <i>(use as many sheets as necessary)</i>			Complete if Known	
Sheet	12	of	12	
			Application Number	10/644,644
			Filing Date	August 19, 2003
			First Named Inventor	Henley, Francois J.
			Art Unit	Not Yet Assigned 2823
			Examiner Name	Not Yet Assigned H. Lee
			Attorney Docket Number	018419-000183US

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T <sup>2</sup>				

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Examiner Signature	<i>Karen Meng Lee</i>	Date Considered	<i>6/22/05</i>
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